

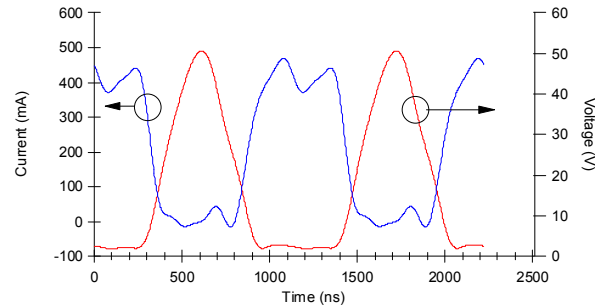
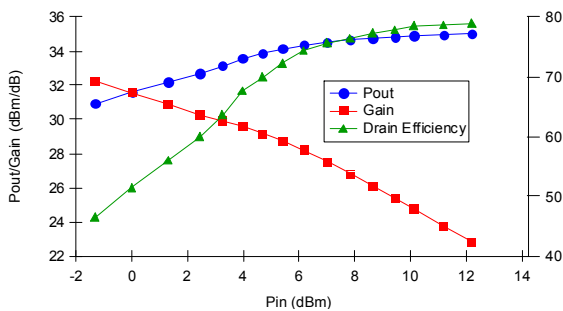
The Impact of System Impedance on the Characterization of High Power Devices

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Outline

- Introduction
 - The use of waveforms in PA design
 - Simulation conditions
- The impact of system impedances on high power and low power devices
 - Low power
 - High power
- Possible solutions

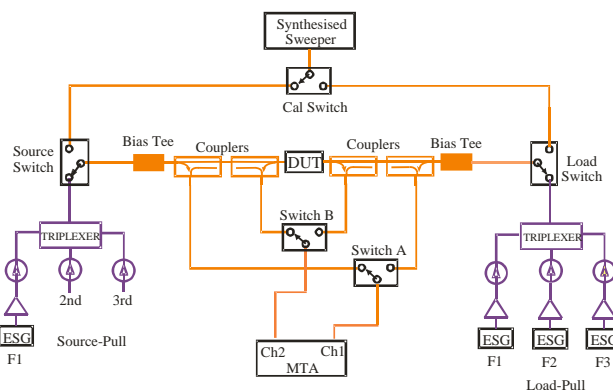
- Waveforms allow for improved amplifier design
- This can only be inferred by the use of power meters and spectrum analysers
- The use of waveforms confirms the behaviour of the device



Simulation set up

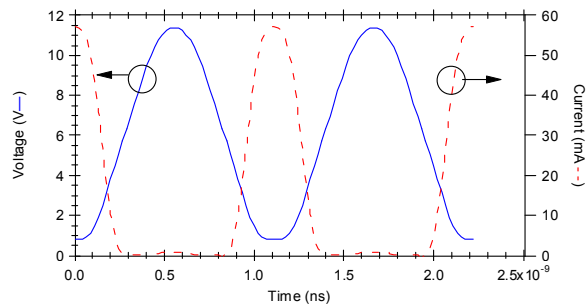
The simulations are done with consideration of the measurement capabilities available at Cardiff University

- The DUT is biased at pinch off (class B)
- The DUT is subjected to 3 harmonic active load pull with the system impedance set to 50Ω for all other frequencies
 - $Z(f_0) = \text{real}$
 - $Z(2f_0) = 0\Omega$
 - $Z(3f_0) = 0\Omega$
- The sources are set to 50Ω



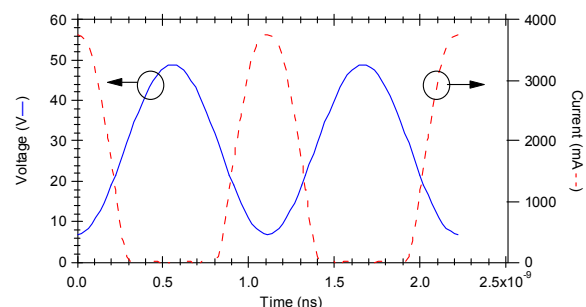
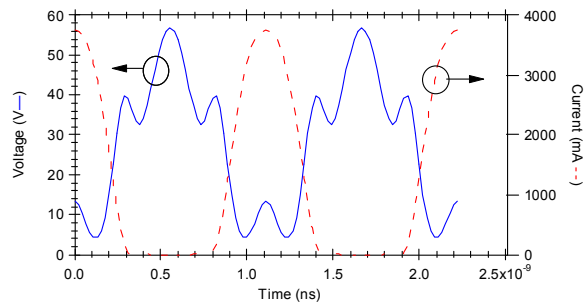
Low power On wafer device

- $Z(f_0) = 250\Omega$
- $Z(2f_0)$ & $Z(3f_0)$ set to a short circuit
- Higher harmonics terminated to 50Ω
- Clean waveforms with little visible effect of higher harmonics
- Fourth and fifth harmonics are 35dBc below the fundamental



High power On wafer device

- $Z(f_0) = 11\Omega$
- $Z(2f_0)$ & $Z(3f_0)$ set to a short circuit
- Higher harmonics terminated to 50Ω
- Heavily distorted voltage waveform
- Fourth harmonic voltage is only 7.8dB below the fundamental
- Device inserted into a 2Ω system environment
- Waveforms have now become a lot cleaner



- A low impedance measurement system
- A 5/7/9/n harmonic load pull measurement system
- Broadband impedance transformers

